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Day : Tuesday
Date: 3/25/2003
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Inventor Name Search Result

Your Search was:

Last Name = NAKATA
First Name = YOSHIRO

Application#	Patent#	Status	Date Filed	Title	Inventor Name
08638038	5829126	150	04/26/1996	METHOD OF MANUFACTURING PROBE CARD	NAKATA , YOSHIRO
08650486	5665610	150	05/17/1996	SEMICONDUCTOR DEVICE CHECKING METHOD	NAKATA , YOSHIRO
06426276	4614586	250	09/29/1982	SEMIPERMEABLE POLYMERIC FILM MEMBRANE	NAKATA , YOSHIRO
07848840	5214296	150	03/10/1992	THIN-FILM SEMICONDUCTOR DEVICE AND METHOD OF FABRICATING THE SAME	NAKATA , YOSHIRO
09176194	6297658	150	10/21/1998	WAFER BURN-IN CASSETTE AND METHOD OF MANUFACTURING PROBE CARD FOR USE THEREIN	NAKATA , YOSHIRO
08943411	5983331	150	09/30/1997	SEMICONDUCTOR INTEGRATED CIRCUIT HAVING A PLURALITY OF CHIPS	NAKATA , YOSHIRO
07882064	5315543	150	05/12/1992	SEMICONDUCTOR MEMORY DEVICE AND A MANUFACTURING METHOD THEREOF	NAKATA , YOSHIRO
07915898	5300814	150	07/17/1992	SEMICONDUCTOR DEVICE HAVING A SEMICONDUCTOR SUBSTRATE WITH REDUCED STEP BETWEEN MEMORY CELLS	NAKATA , YOSHIRO
08065123	5355081	150	05/20/1993	A METHOD FOR TESTING A SEMICONDUCTOR INTEGRATED CIRCUIT HAVING SELF TESTING CIRCUIT	NAKATA , YOSHIRO

07456994	5006717	150	12/26/1989	METHOD OF EVALUATING A SEMICONDUCTOR DEVICE AND AN APPARATUS FOR PERFORMING THE SAME	NAKATA , YOSHIRO
07710788	Not Issued	161	06/05/1991	SEMICONDUCTOR MEMORY DEVICE AND ITS FABRICATING METHOD	NAKATA , YOSHIRO
09174536	6518779	150	10/19/1998	PROBE CARD	NAKATA , YOSHIRO
08530428	Not Issued	166	09/19/1995	A SEMICONDUCTOR INTEGRATED CIRCUIT HAVING A PLURALITY OF CHIPS	NAKATA , YOSHIRO
08257955	5399890	150	06/10/1994	SEMICONDUCTOR MEMORY DEVICE IN WHICH A CAPACITOR ELECTRODE OF A MEMORY CELL AND AN INTERCONNECTION LAYER OF A PERIPHERAL CIRCUIT ARE FORMED IN ONE LEVEL	NAKATA , YOSHIRO
07699950	Not Issued	166	05/14/1991	SEMICONDUCTOR MEMORY DEVICE CAPACITOR HAVING PLURAL PARALLEL PLATE ELECTRODES AND CONNECTING SIDE-WALL ELECTRODE	NAKATA , YOSHIRO
07683603	5217914	150	04/10/1991	METHOD FOR MAKING SEMICONDUCTOR INTEGRATION CIRCUIT WITH STACKED CAPACITOR CELLS	NAKATA , YOSHIRO
07678150	5241201	150	04/02/1991	DRAM WITH CONCENTRIC ADJACENT CAPACITORS	NAKATA , YOSHIRO
08575735	5825193	150	12/18/1995	SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE	NAKATA , YOSHIRO
09140323	6229329	150	08/26/1998	METHOD OF TESTING ELECTRICAL CHARACTERISTICS OF MULTIPLE SEMICONDUCTOR INTEGRATED CIRCUITS SIMULTANEOUSLY	NAKATA , YOSHIRO

08624954	5605844	150	03/27/1996	INSPECTING METHOD FOR SEMICONDUCTOR DEVICES	NAKATA , YOSHIRO
08060695	Not Issued	161	05/13/1993	SEMICONDUCTOR MEMORY DEVICE CAPACITOR HAVING PLURAL PARALLEL PLATE ELECTRODES AND CONNECTING SIDE-WALL ELECTRODES	NAKATA , YOSHIRO
07767998	5248936	150	09/30/1991	SEMICONDUCTOR INTEGRATED CIRCUIT AND A METHOD OF TESTING THE SAME	NAKATA , YOSHIRO
08744082	5892368	150	11/04/1996	SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE HAVING FAILURE DETECTION CIRCUITRY	NAKATA , YOSHIRO
07964720	Not Issued	166	10/22/1992	SEMICONDUCTOR MEMORY AND METHOD OF FABRICATING THE SAME	NAKATA , YOSHIRO
09198445	6215321	150	11/24/1998	PROBE CARD FOR WAFER-LEVEL MEASUREMENT, MULTILAYER CERAMIC WIRING BOARD, AND FABRICATING METHODS THEREFOR	NAKATA , YOSHIRO
07310624	Not Issued	166	02/15/1989	MOLDABLE COMPOSITION, PROCESS FOR PRODUCING SINTERED BODY THEREFROM AND PRODUCTS FROM SAME	NAKATA , YOSHIROH
07733979	5432224	150	07/22/1991	MOLDABLE COMPOSITION, PROCESS FOR PRODUCING SINTERED BODY THEREFROM AND PRODUCTS FROM SAME	NAKATA , YOSHIROH
08358609	Not Issued	166	12/14/1994	SEMICONDUCTOR WAFER PACKAGE, METHOD AND APPARATUS FOR CONNECTING TESTING IC TERMINALS OF SEMICONDUCTOR WAFER AND PROBE TERMINALS, TESTING METHOD OF A SEMICONDUCTOR INTEGRATED CIRCUIT,	NAKATA , YOSHIROU

				PROBE CARD AND ITS MANUFACTURING METHOD	
09396884	6323663	150	09/16/1999	SEMICONDUCTOR WAFER PACKAGE, METHOD AND APPARATUS FOR CONNECTING TESTING IC TERMINALS OF SEMICONDUCTOR WAFER AND PROBE TERMINALS, TESTING METHOD OF A SEMICONDUCTOR INTEGRATED CIRCUIT, PROBE CARD AND ITS MANUFACTURING METHOD	NAKATA , YOSHIROU
08837954	6005401	150	04/14/1997	SEMICONDUCTOR WAFER PACKAGE, METHOD AND APPARATUS FOR CONNECTING TESTING IC TERMINALS OF SEMICONDUCTOR WAFER AND PROBE TERMINALS, TESTING METHOD OF A SEMICONDUCTOR INTEGRATED CIRCUIT, PROBE CARD AND ITS MANUFACTURING METHOD	NAKATA , YOSHIROU
08609150	5945834	150	02/29/1996	SEMICONDUCTOR WAFER PACKAGE, METHOD AND APPARATUS FOR CONNECTING TESTING IC TERMINALS OF SEMICONDUCTOR WAFER AND PROBE TERMINALS, TESTING METHOD OF A SEMICONDUCTOR INTEGRATED CIRCUIT, PROBE CARD AND ITS MANUFACTURING METHOD	NAKATA , YOSHIROU
09964480	Not Issued	030	09/28/2001	SEMICONDUCTOR INTEGRATED CIRCUIT TESTING SYSTEM AND METHOD	NAKATA, YOSHIRO
10322571	Not Issued	030	12/19/2002	METHOD OF TESTING SEMICONDUCTOR	NAKATA, YOSHIRO

				INTEGRATED CIRCUITS AND TESTING BOARD FOR USE THEREIN	
09811422	6400175	150	03/20/2001	METHOD OF TESTING SEMICONDUCTOR INTEGRATED CIRCUITS AND TESTING BOARD FOR USE THEREIN	NAKATA, YOSHIRO
10127580	Not Issued	041	04/23/2002	METHOD OF TESTING SEMICONDUCTOR INTEGRATED CIRCUITS AND TESTING BOARD FOR USE THEREIN	NAKATA, YOSHIRO
08088908	Not Issued	166	07/08/1993	IMAGE RECORDING APPARATUS	NAKATANI , YOSHIRO

Inventor Search Completed: No Records to Display.

Search Another: Inventor

Last Name nakata **First Name** yoshiro

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